

Description

The HSP60N06 is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

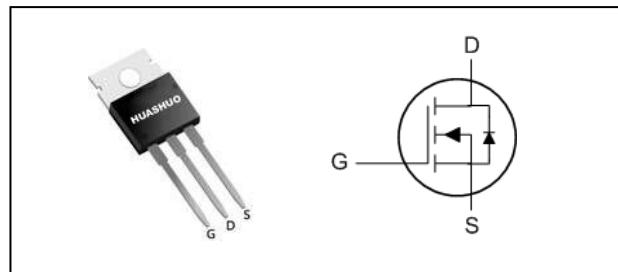
The HSP60N06 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

- 100% EAS Guaranteed
- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

Product Summary

| | | |
|-----------------------|----|----|
| V _{DS} | 60 | V |
| R _{DSON,typ} | 12 | mΩ |
| I _D | 60 | A |

TO-220 Pin Configuration



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|--------------------------------------|--|------------|-------|
| V _{DS} | Drain-Source Voltage | 60 | V |
| V _{GS} | Gate-Source Voltage | ±20 | V |
| I _D @T _c =25°C | Continuous Drain Current, V _{GS} @ 10V ¹ | 60 | A |
| I _D @T _c =70°C | Continuous Drain Current, V _{GS} @ 10V ¹ | 41 | A |
| I _{DM} | Pulsed Drain Current ² | 110 | A |
| EAS | Single Pulse Avalanche Energy ³ | 70 | mJ |
| I _{AS} | Avalanche Current | 38 | A |
| P _D @T _c =25°C | Total Power Dissipation ⁴ | 85 | W |
| T _{STG} | Storage Temperature Range | -55 to 150 | °C |
| T _J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|------------------|--|------|------|------|
| R _{θJA} | Thermal Resistance Junction-Ambient ¹ | --- | 62 | °C/W |
| R _{θJC} | Thermal Resistance Junction-Case ¹ | --- | 1.4 | °C/W |

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

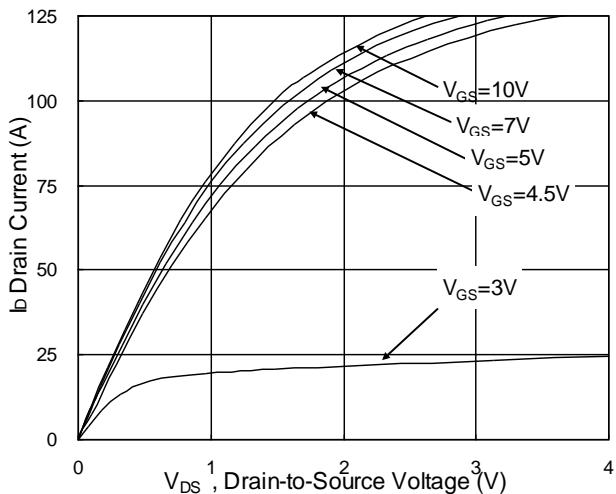
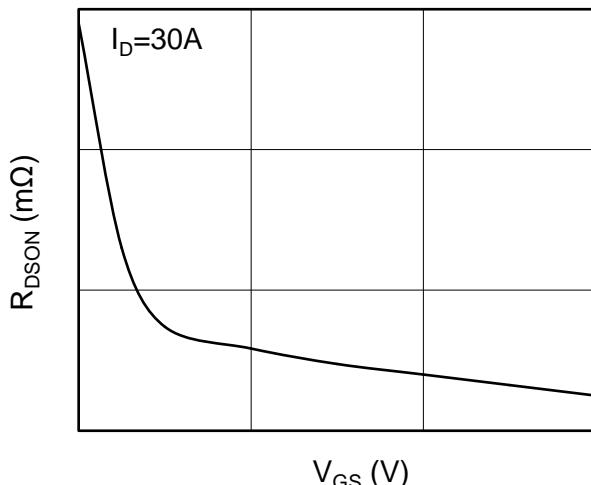
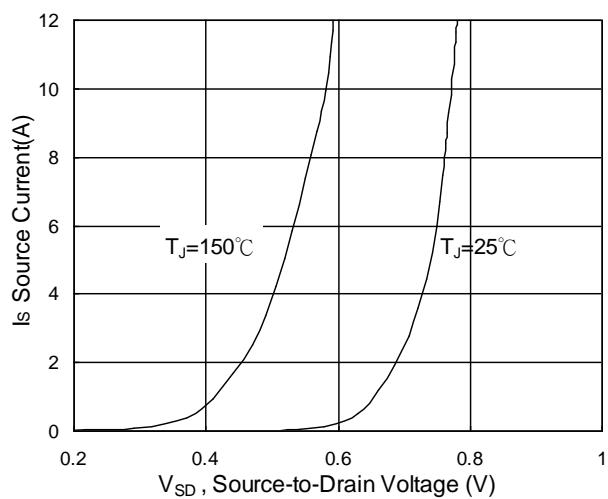
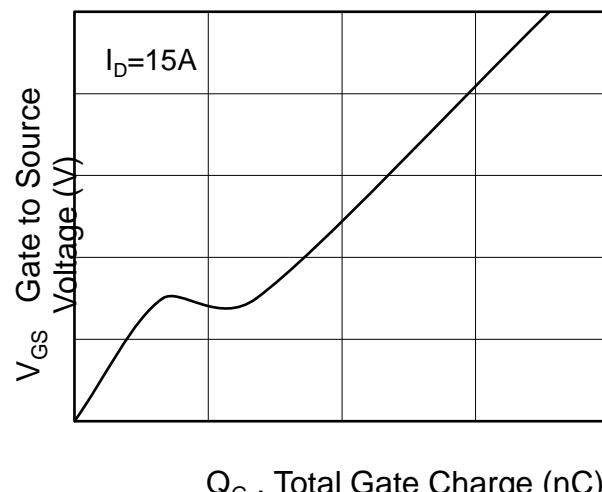
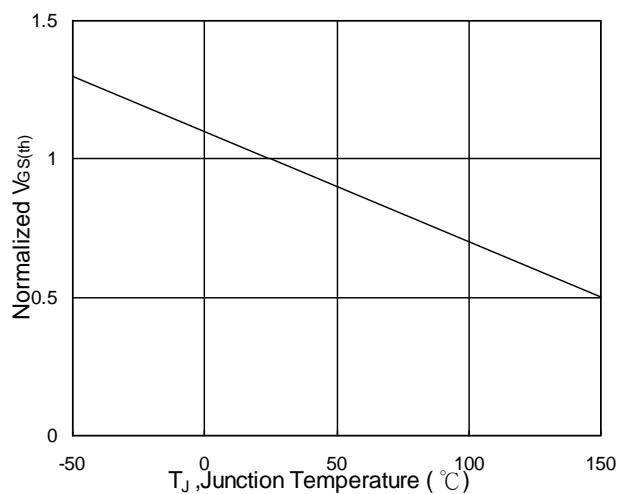
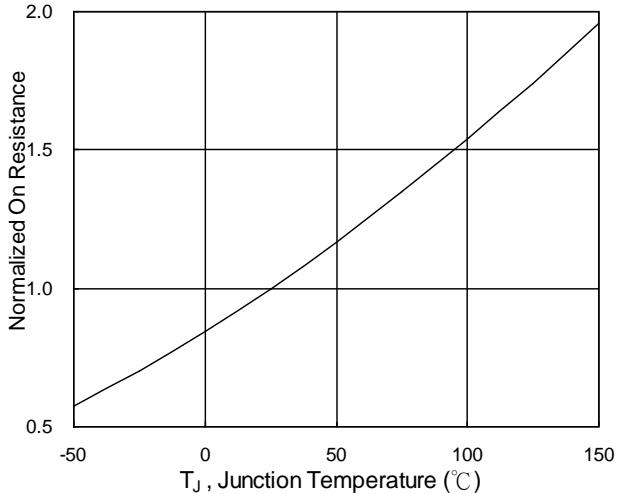
| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-------------------------------------|--|---|------|-------|------|-------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250uA | 60 | --- | --- | V |
| △BV _{DSS} /△T _J | BV _{DSS} Temperature Coefficient | Reference to 25°C, I _D =1mA | --- | 0.052 | --- | V/°C |
| R _{DS(ON)} | Static Drain-Source On-Resistance ² | V _{GS} =10V, I _D =30A | --- | 12 | 16 | mΩ |
| | | V _{GS} =4.5V, I _D =15A | --- | 14 | 20 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =250uA | 1.2 | 1.7 | 2.5 | V |
| △V _{GS(th)} | V _{GS(th)} Temperature Coefficient | | --- | -5.76 | --- | mV/°C |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =48V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | uA |
| | | V _{DS} =48V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| I _{GSS} | Gate-Source Leakage Current | V _{GS} =±20V, V _{DS} =0V | --- | --- | ±100 | nA |
| g _{fs} | Forward Transconductance | V _{DS} =5V, I _D =30A | --- | 45 | --- | S |
| R _g | Gate Resistance | V _{DS} =0V, V _{GS} =0V, f=1MHz | --- | 1.7 | --- | Ω |
| Q _g | Total Gate Charge (4.5V) | V _{DS} =48V, V _{GS} =4.5V, I _D =15A | --- | 23 | --- | nC |
| Q _{gs} | Gate-Source Charge | | --- | 7.5 | --- | |
| Q _{gd} | Gate-Drain Charge | | --- | 7.9 | --- | |
| T _{d(on)} | Turn-On Delay Time | V _{DD} =30V, V _{GS} =10V, R _G =3.3Ω, I _D =15A | --- | 7.4 | --- | ns |
| T _r | Rise Time | | --- | 50 | --- | |
| T _{d(off)} | Turn-Off Delay Time | | --- | 36 | --- | |
| T _f | Fall Time | | --- | 7.8 | --- | |
| C _{iss} | Input Capacitance | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 2840 | --- | pF |
| C _{oss} | Output Capacitance | | --- | 150 | --- | |
| C _{rss} | Reverse Transfer Capacitance | | --- | 106 | --- | |

Diode Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-----------------|--|--|------|------|------|------|
| I _s | Continuous Source Current ^{1,5} | V _G =V _D =0V, Force Current | --- | --- | 60 | A |
| I _{SM} | Pulsed Source Current ^{2,5} | | --- | --- | 90 | A |
| V _{SD} | Diode Forward Voltage ² | V _{GS} =0V, I _s =A, T _J =25°C | --- | --- | 1.2 | V |
| t _{rr} | Reverse Recovery Time | I _F =15A, dI/dt=100A/μs, T _J =25°C | --- | 16 | --- | nS |
| Q _{rr} | Reverse Recovery Charge | | --- | 11 | --- | nC |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD}=25V,V_{GS}=10V,L=0.1mH,I_{AS}=38A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

Fig.1 Typical Output Characteristics

Fig.2 On-Resistance v.s Gate-Source

Fig.3 Forward Characteristics of Reverse

Fig.4 Gate-Charge Characteristics

Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.6 Normalized $R_{DS(on)}$ vs. T_J



HUASHUO
SEMICONDUCTOR

HSP60N06

N-Ch 60V Fast Switching MOSFETs

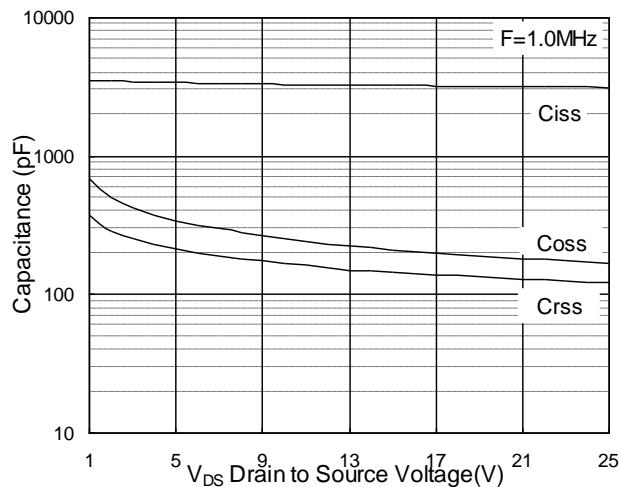


Fig.7 Capacitance

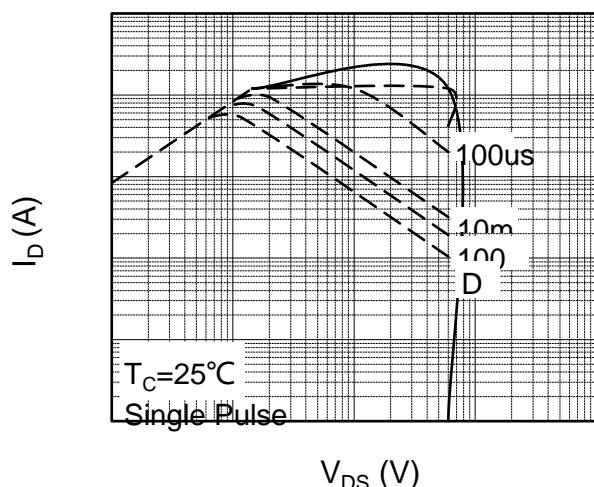


Fig.8 Safe Operating Area

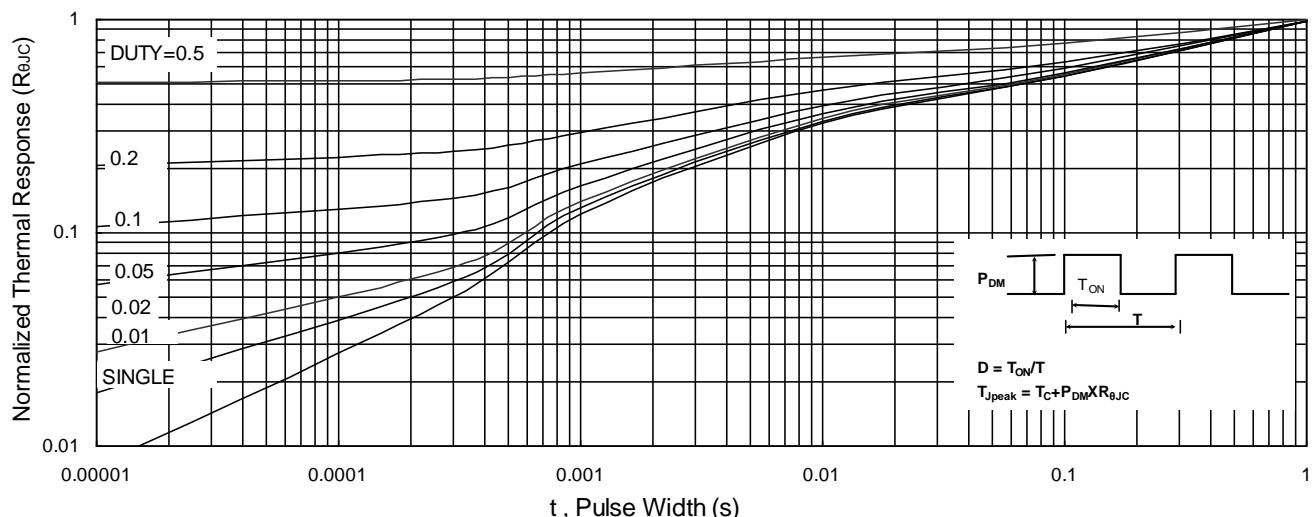


Fig.9 Normalized Maximum Transient Thermal Impedance

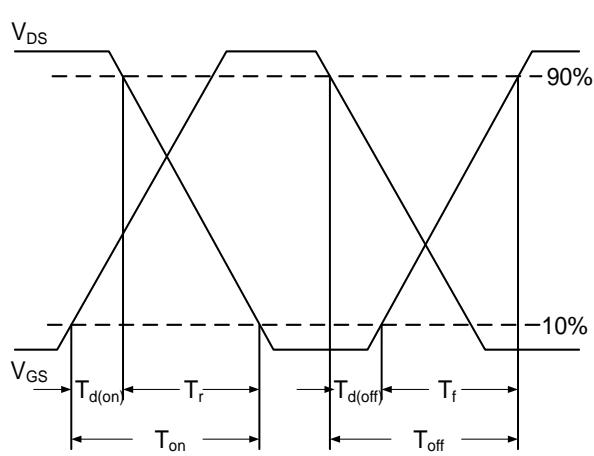


Fig.10 Switching Time Waveform

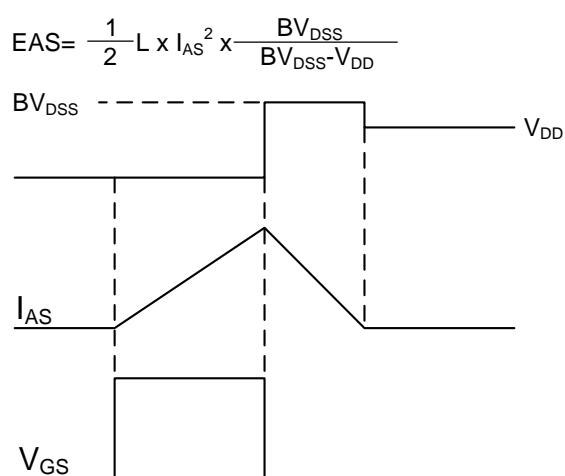
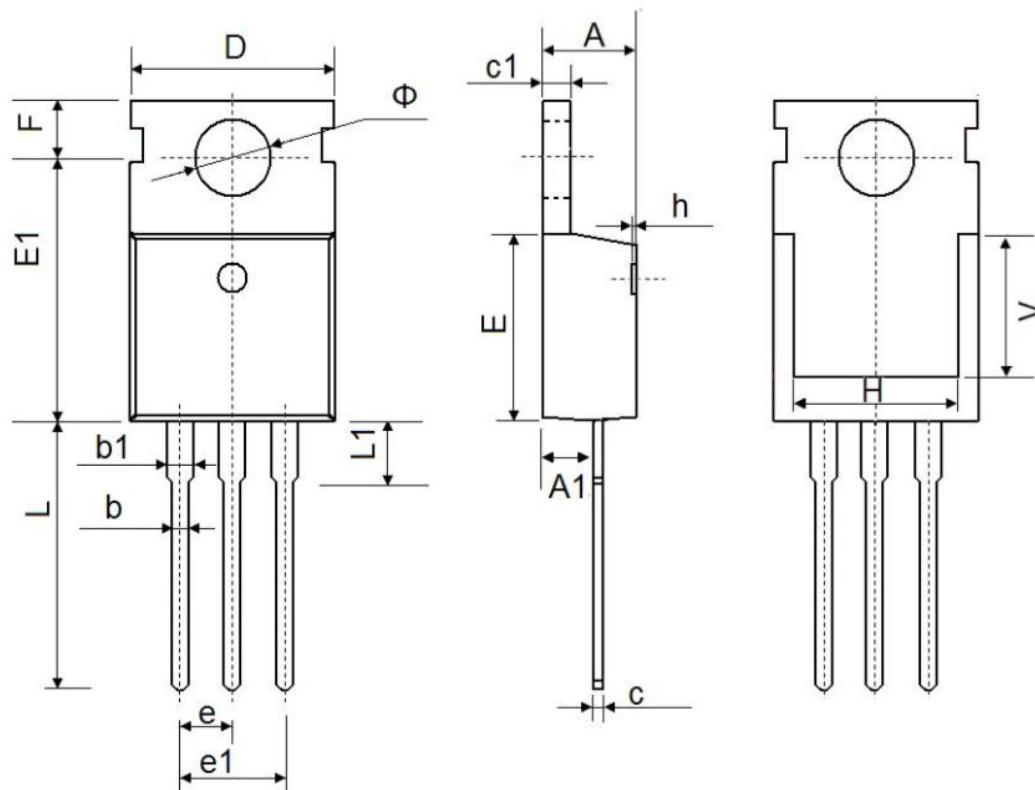


Fig.11 Unclamped Inductive Switching Waveform



TO-220 Package Information



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|--------|----------------------|-------|
| | Min. | Max. | Min. | Max |
| A | 4.300 | 4.700 | 0.169 | 0.185 |
| A1 | 2.200 | 2.600 | 0.087 | 0.102 |
| b | 0.700 | 0.950 | 0.028 | 0.037 |
| b1 | 1.170 | 1.410 | 0.046 | 0.056 |
| c | 0.450 | 0.650 | 0.018 | 0.026 |
| c1 | 1.200 | 1.400 | 0.047 | 0.055 |
| D | 9.600 | 10.400 | 0.378 | 0.409 |
| E | 8.8500 | 9.750 | 0.348 | 0.384 |
| E1 | 12.650 | 12.950 | 0.498 | 0.510 |
| e | 2.540 TYP. | | 0.100TYP. | |
| e1 | 4.980 | 5.180 | 0.196 | 0.204 |
| F | 2.650 | 2.950 | 0.104 | 0.116 |
| H | 7.900 | 8.100 | 0.311 | 0.319 |
| h | 0.000 | 0.300 | 0.000 | 0.012 |
| L | 12.750 | 14.300 | 0.502 | 0.563 |
| L1 | 2.850 | 3.950 | 0.112 | 0.156 |
| V | 7.500 REF. | | 0.295 REF. | |
| Φ | 3.400 | 4.000 | 0.134 | 0.157 |